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Investigation of the compatibility of X-CT measurement data to surface topography analysis

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I. Introduction

In recent years X-CT metrology becomes more popular as a promising geometrical measurement technique. In comparison to traditional tactile and optical metrology techniques, X-CT has the unique advantage: it is a non-destructive method which can measure both the complete internal and external geometry without constraint. Although X-CT has a limitation on the measurement of surface texture due to limited resolution, it is qualified for that of most of additive processed surfaces, which are featured by high roughness surface texture comprising a number of topographical features, such as bumps, step markings and surface pores.

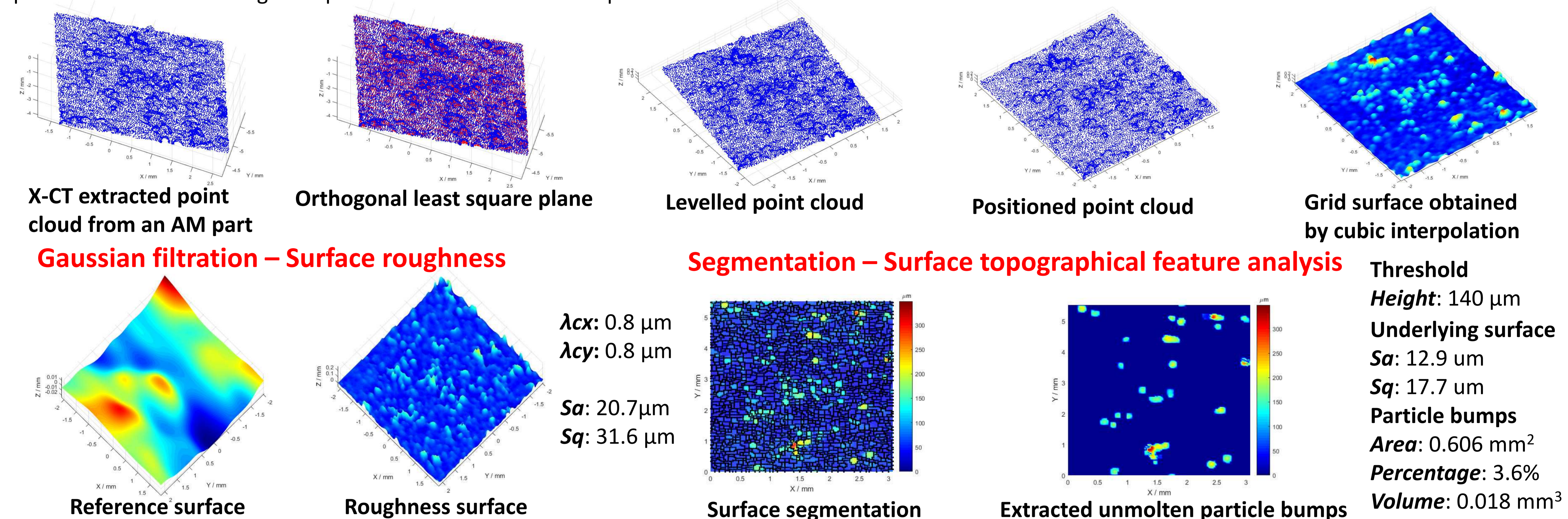
The X-CT generated data structures for the object surface, either point cloud or triangular mesh, differ from the grid structure of traditional surface measurement data. To enable X-CT data structures compatible with surface characterisation, two strategies are investigated. One is to interpolate scattered points into grid structure. The other is to perform surface analysis directly on triangular mesh.

II. Comparison of different data structures

	Pros	Cons
Grid data	<ol style="list-style-type: none"> 1. Default data structure for surface evaluation. All surface analysis software can support. 2. The connection of measured points is well defined. 	<ol style="list-style-type: none"> 1. Not straightforward available from CT. 2. They are specified by heights over the sampling plane, e.g. $z = f(x, y)$. Not suitable for surfaces with complex geometry.
Triangular mesh	<ol style="list-style-type: none"> 1. More general data structure. Specified by (x, y, z) and point connections. Suitable for surfaces with complex geometry. 2. Available from CT. 3. The connections of measured points are well defined. 	<ol style="list-style-type: none"> 1. No commercial surface analysis software support triangular mesh. 2. Not clear how triangular mesh is generated from point cloud by CT software.
Point cloud	<ol style="list-style-type: none"> 1. Directly available from CT and most "reliable". 	<ol style="list-style-type: none"> 1. Raw data structure. Discrete points specified by (x, y, z) without connection. 2. Estimate where the surface is. 3. Surface analysis software does not support point cloud.

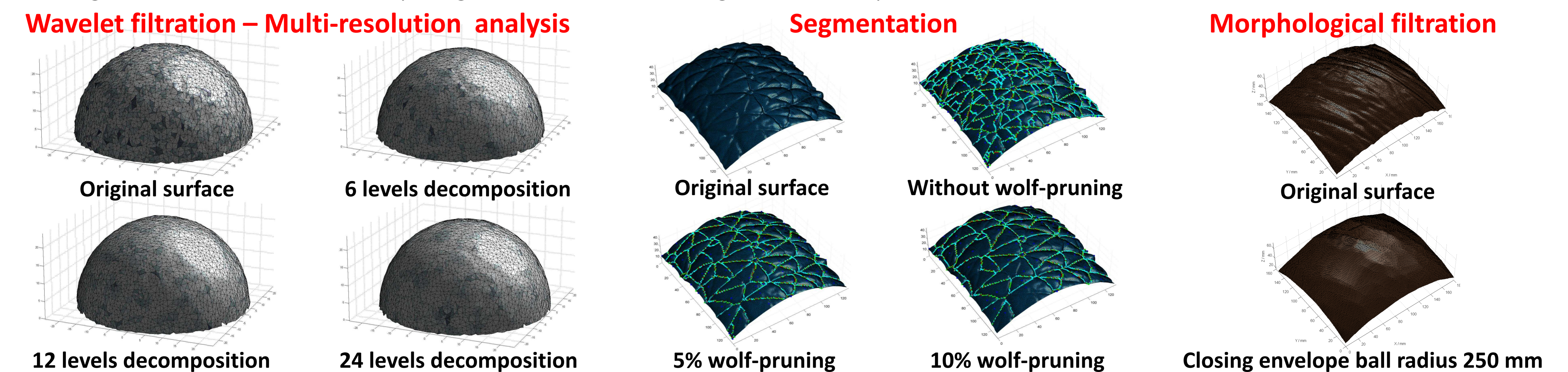
III. Strategy A: point cloud to uniform grid

Point cloud is interpolated into grid data and thereafter conventional surface analysis techniques are applicable. This is suitable for surface data having nearly planar form. The following example illustrates the conversion procedure.



IV. Strategy B: triangular mesh

Triangular mesh is suitable for describing surfaces in complex shapes. A toolbox is under development for supporting surface analysis on triangular mesh, including PDE based Gaussian filter, morphological filter, wavelet filter, segmentation and parameterization.



V. Conclusion & Future work

Two data structures, i.e. surface point cloud and triangular mesh, provided by X-CT are not straightforward compatible to conventional surface analysis techniques. To enable that, point cloud needs to be interpolated into grid structure, or surface analysis techniques enhanced to support triangular mesh. Grid interpolation is a faster and easier way but its usage can be limited. The point connection of triangular mesh can better determine the surface especially in case of complex geometry, therefore it is more capable but challenging.

Further work is to explore feasible ways to bridge X-CT metrology and surface metrology. The development of surface analysis and parameterisation tools for triangular mesh will be focused.

VI. Acknowledgement

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